

SCANNING μ X RAY EXCITED LUMINESCENCE IN SEMICONDUCTORS

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ID22-ESRF

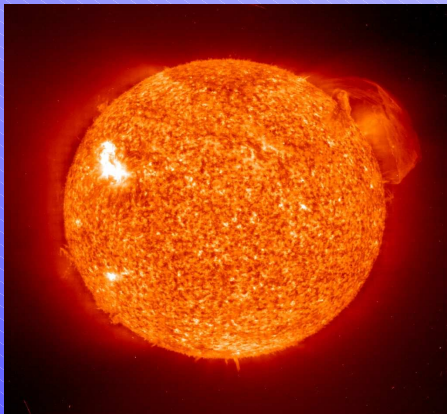
TALK OUTLINE

- Why luminescence ?
- What is the connection with X ray microprobe ?
- Design and setting up
- First tests and preliminary conclusions
- The XEOL upgrade – some key points
- Next experiments

LIGHT EMISSION

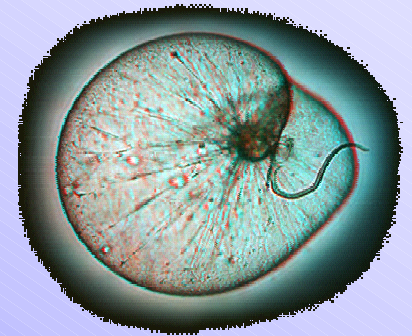
Incandescence

- from a hot object -



Luminescence

- from a "cold" object -



Phosphorescence

- slow emission decay (sec) -

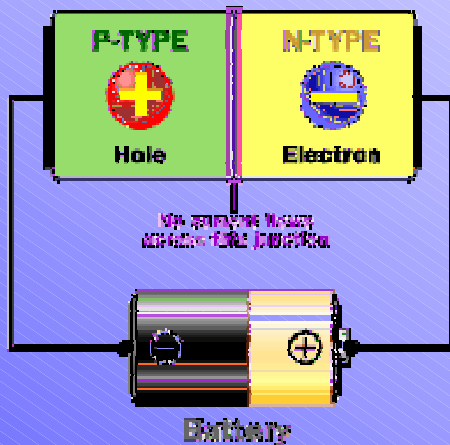


Fluorescence

- fast emission decay (nsec) -



WHY LUMINESCENCE FROM SEMICONDUCTORS ?

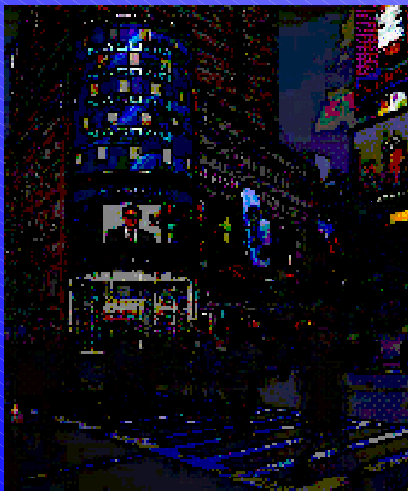


ADVANTAGES:

- Do not get specially hot
- Last much longer
- More durable because of their small plastic bulb
- Fit easily in electronic circuits
- Very HIGH EFFICIENCY
- LOWER COST in the long run

Dozens of different jobs:

Full-color screens



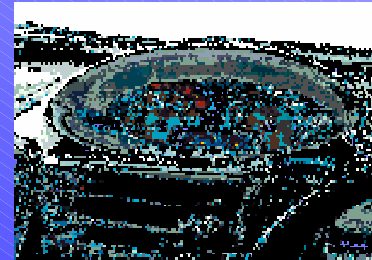
Indoor Lighting



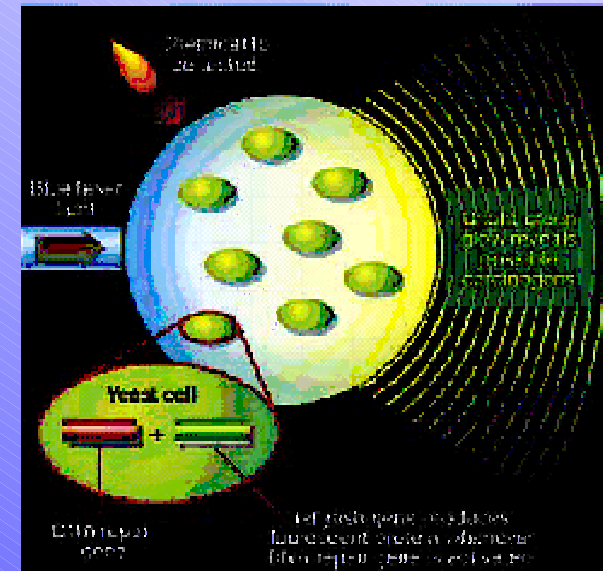
Optical Data Storage



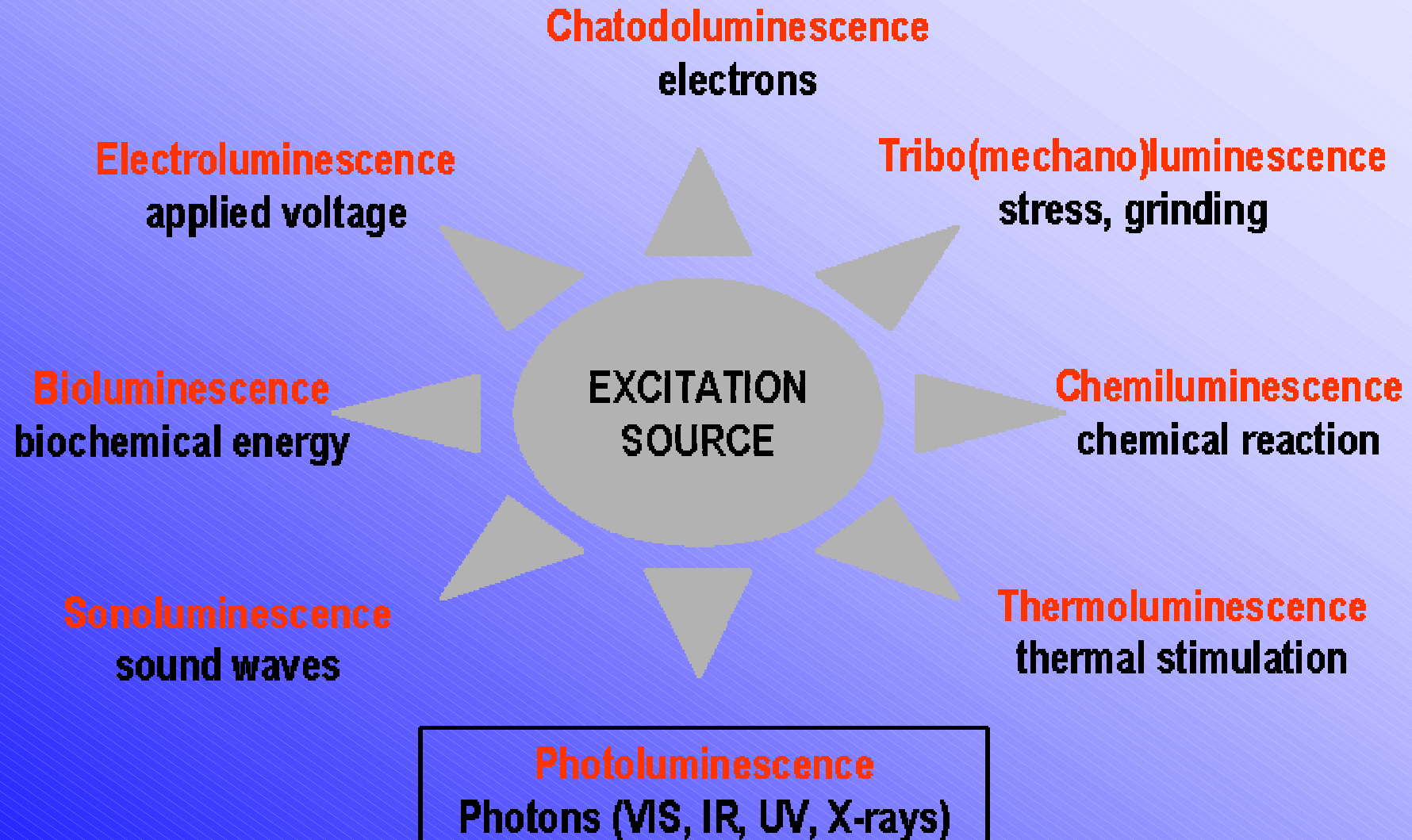
Automotive Displays



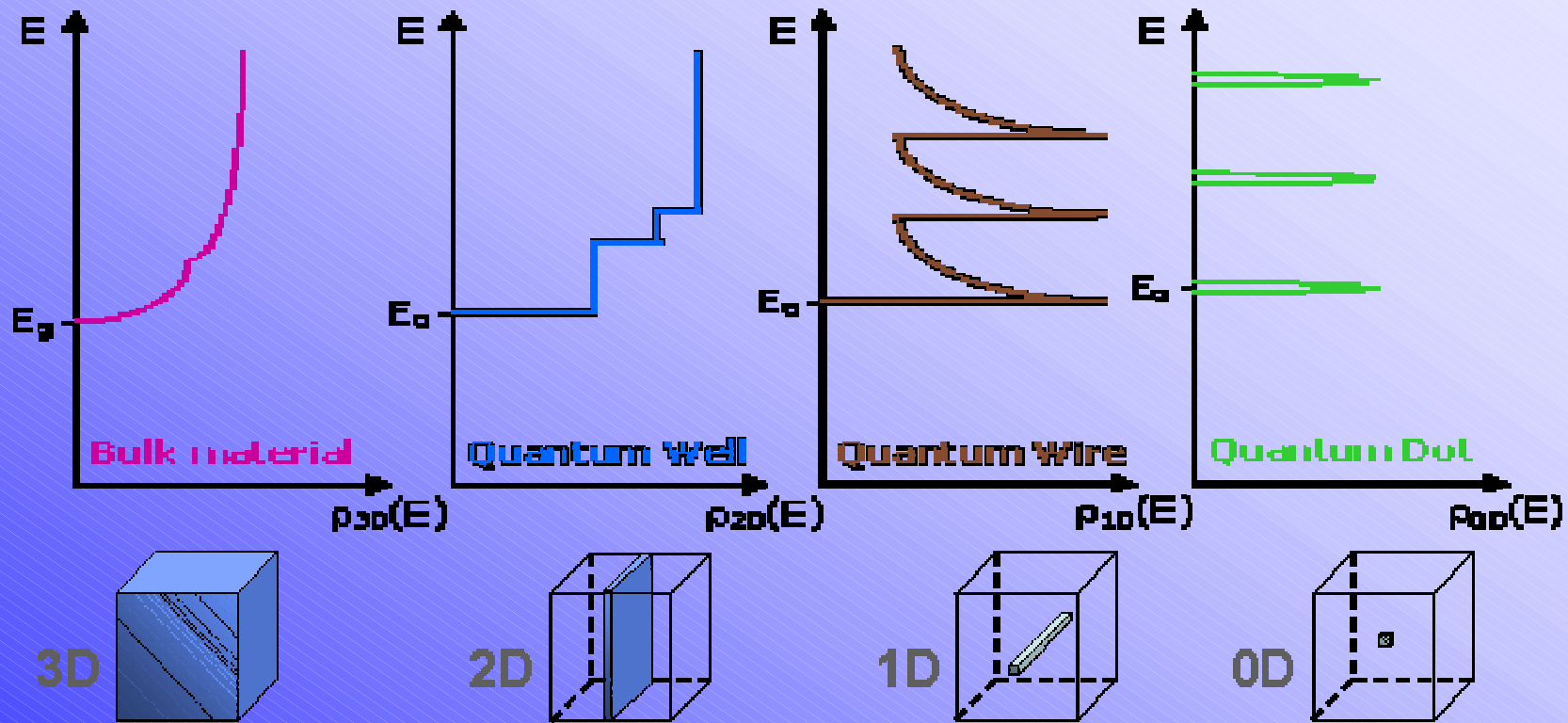
Gentronix: Blue laser light reveals cancer-causing chemicals using yeast cells



HOW CAN LUMINESCENCE BE STUDIED ?



WHAT DOES CONFINEMENT DO IN SEMICONDUCTORS ?

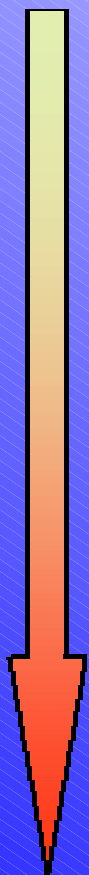


BENEFITS

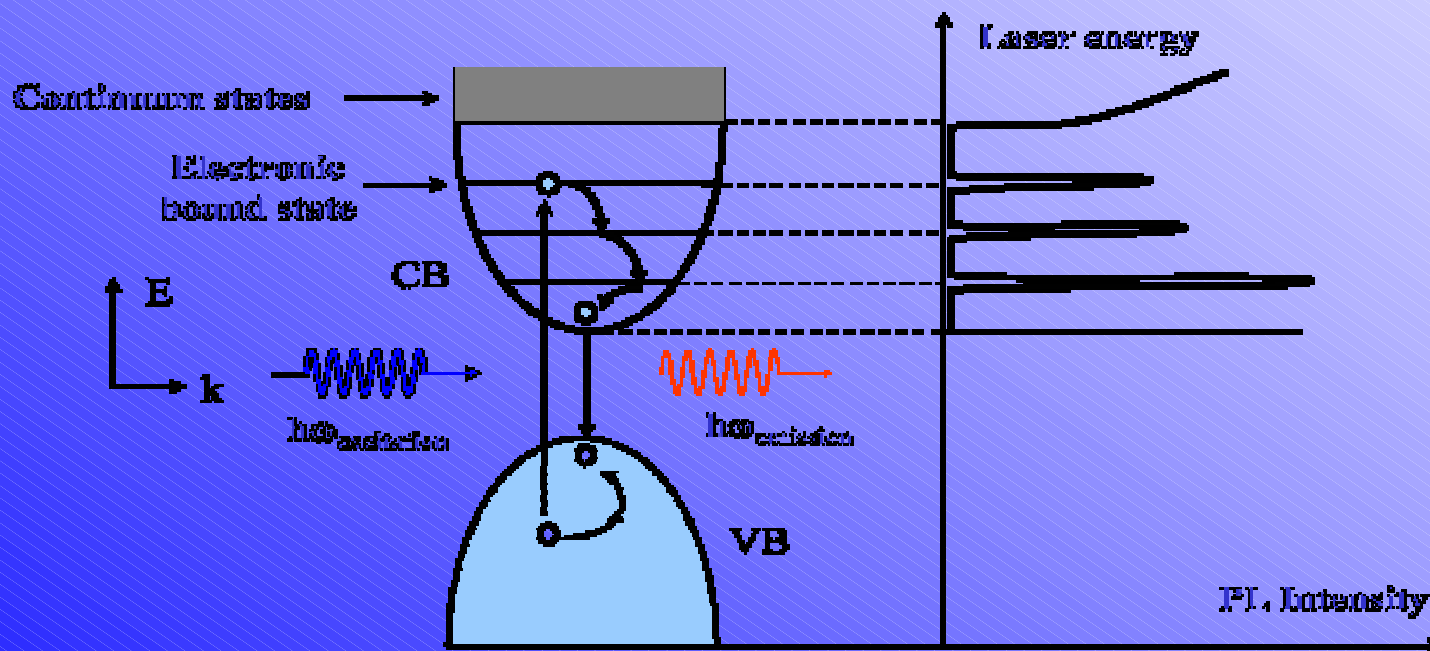
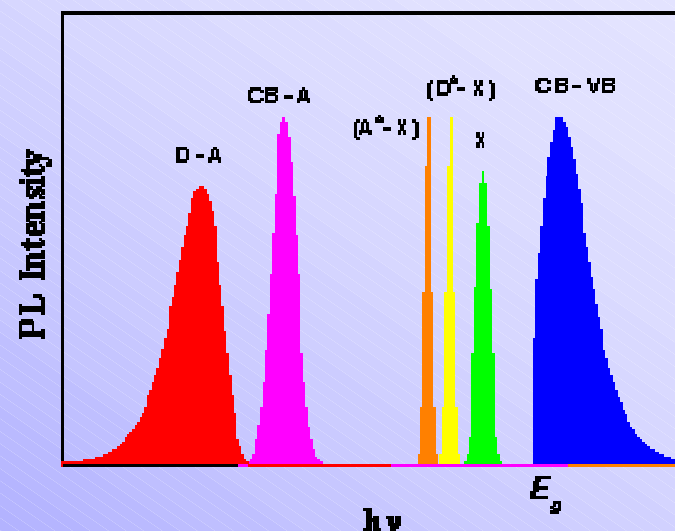
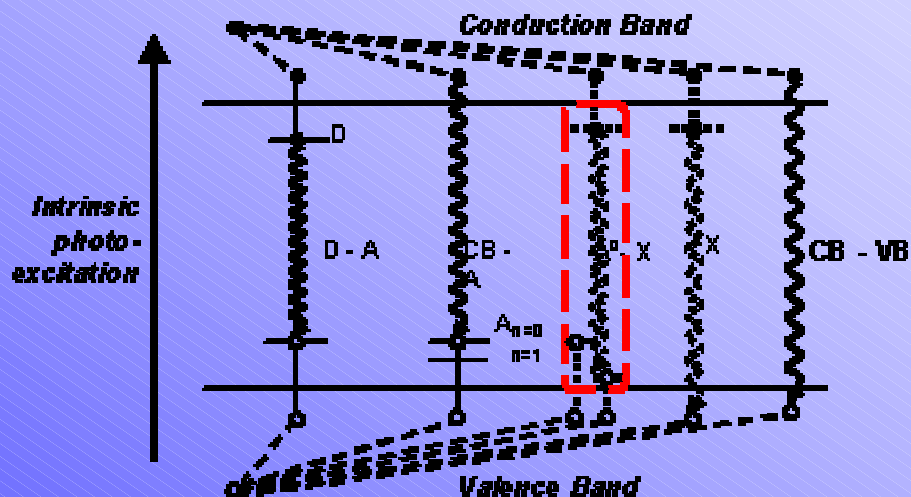
- Sharper wavelength discrimination
- Much higher efficiency
- Much lower thresholds
- Less thermal dependence, spectral broadening
- Enhances optical nonlinear effects
- CREATES WELL-CONTROLLED LUMINESCENCE BANDS

HOW DOES CONFINEMENT CHANGE PHOTOLUMINESCENCE ?

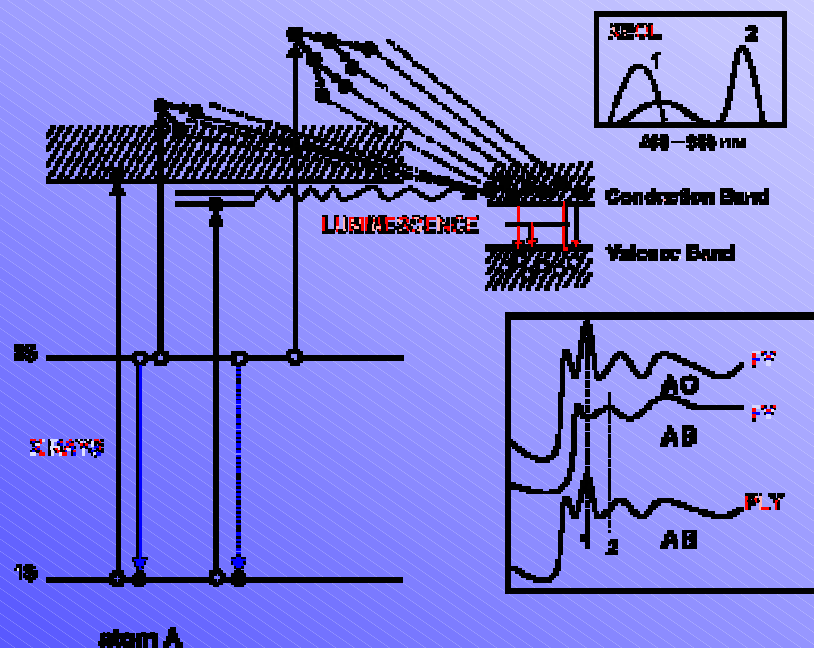
3D



0D



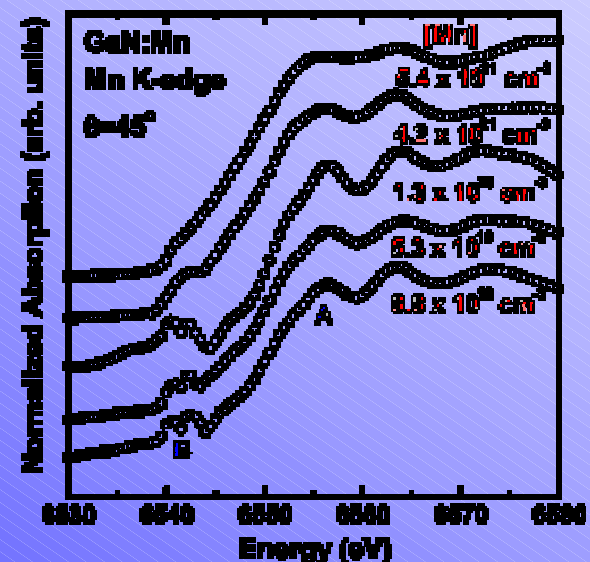
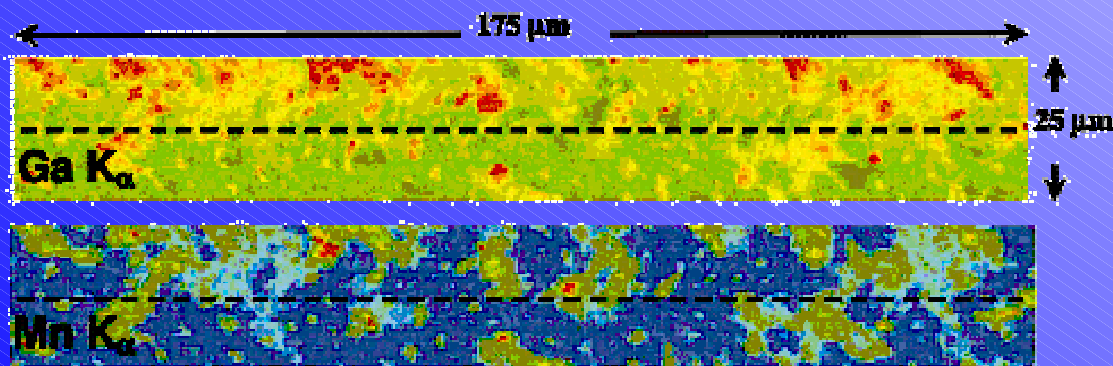
WHAT IS THE CONNECTION WITH X-RAY MICROPROBE ?



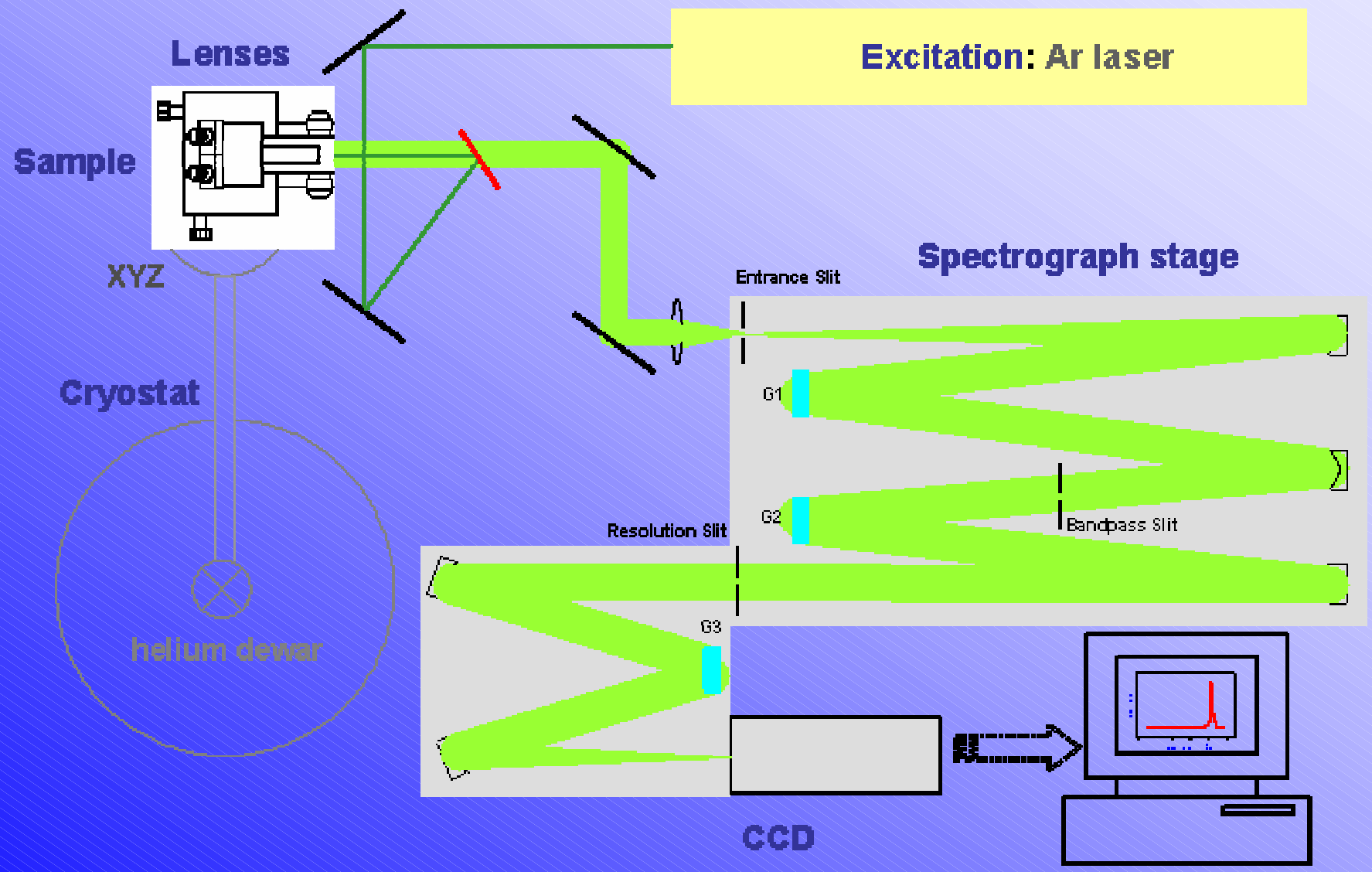
ADVANTAGES:

- XEOL experiments are site selective (under favorable conditions)
- Energy tunability – sampling in depth
- Sensitive to optical centers at low densities
- Imaging on micrometer scale: elements + optical centers
- Non-linear effects (bi-excitonic molecule, etc)
- Can be combined with other techniques: XRF, XRD.

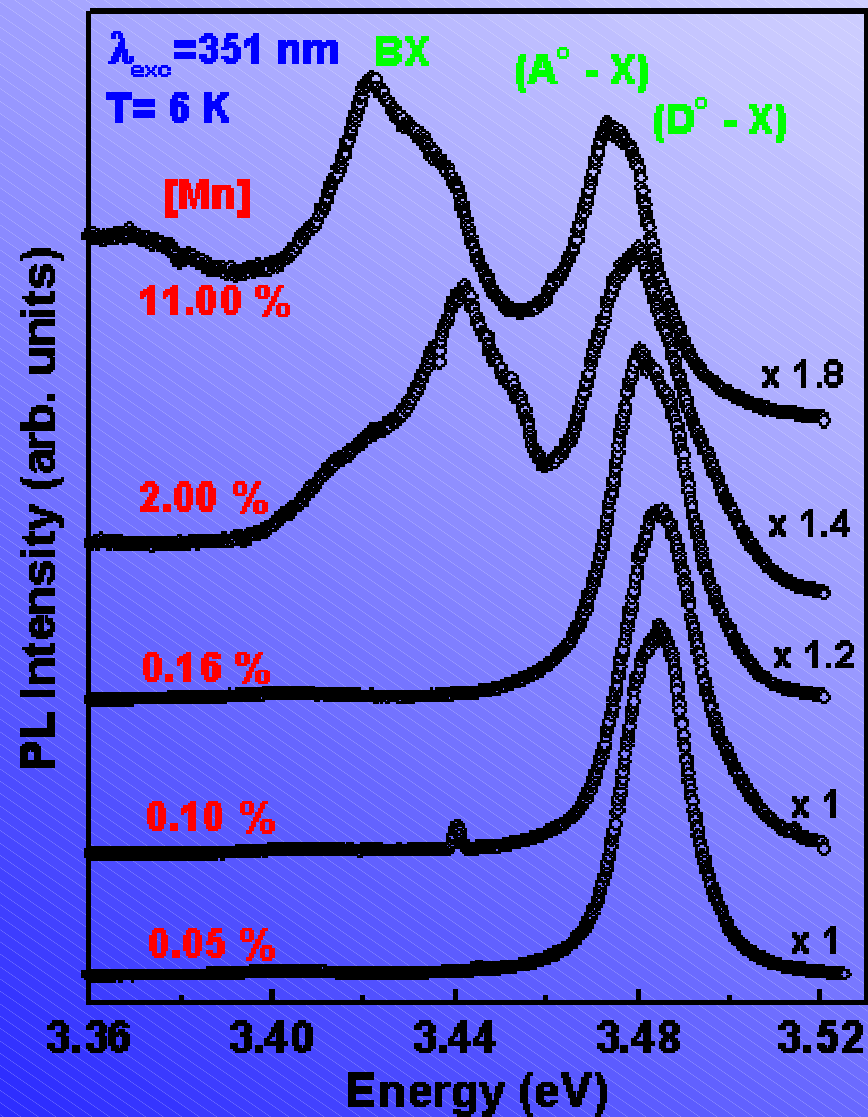
Goals:



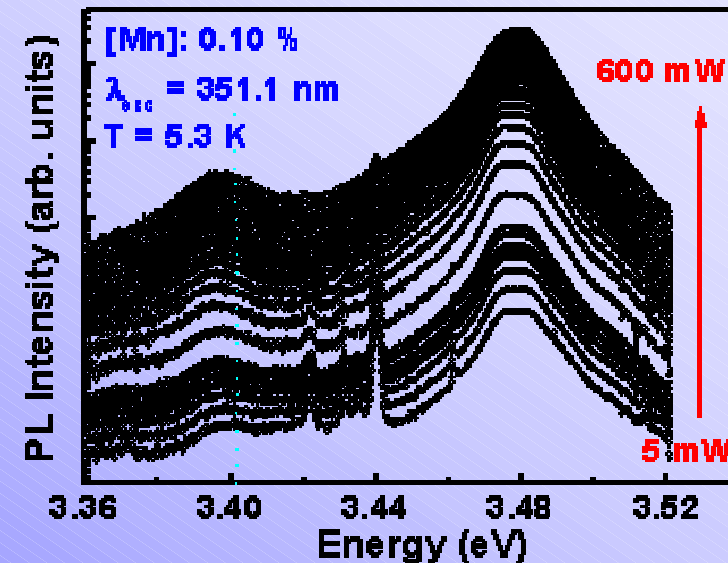
WHAT DO WE NEED TO SET μ -PHOTOLUMINESCENCE UP ?



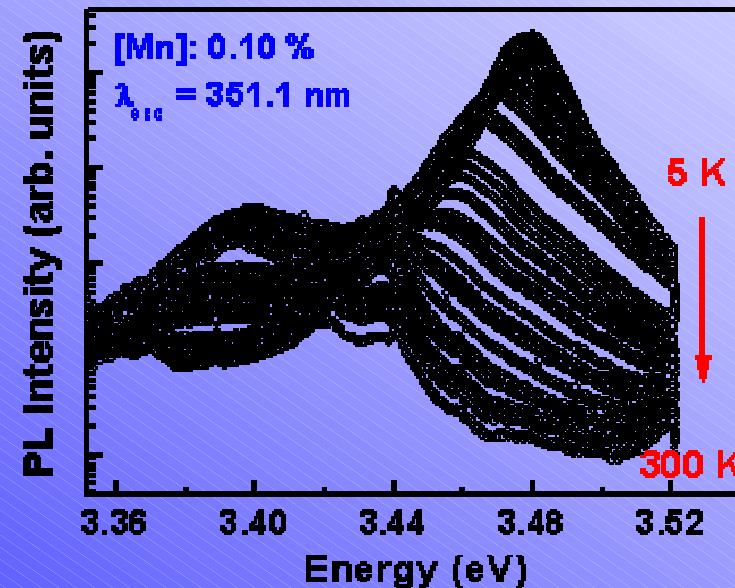
WHAT DOES Ar LASER EXCITED LUMINESCENCE TELL US ?



PHOTOLUMINESCENCE vs EXCITATION POWER

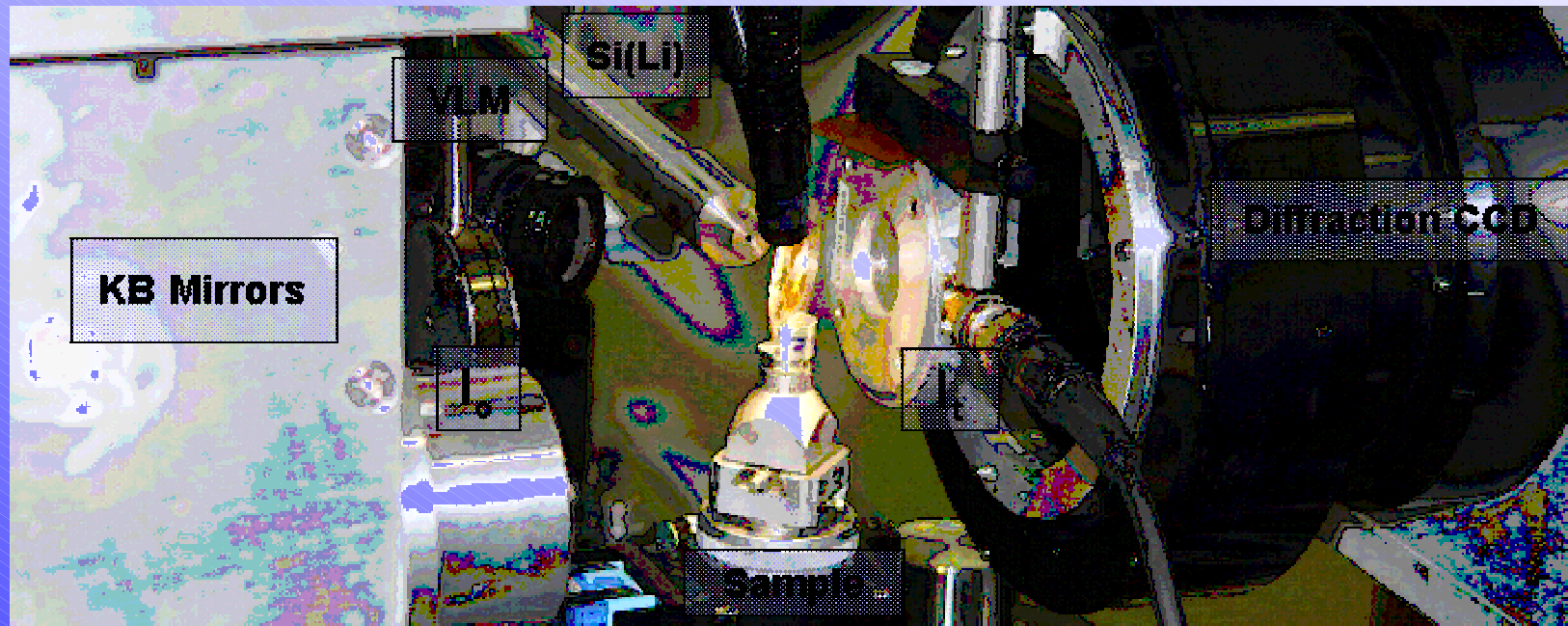


PHOTOLUMINESCENCE vs TEMPERATURE

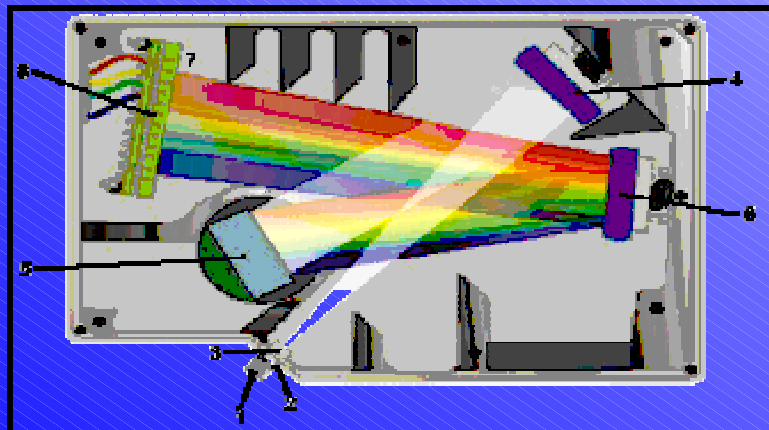


● $h\nu_{BX} = E_g - R_X - E_{BX}$

SCIENTIFIC & TECHNICAL LIMITS -> COST/PRICE RATIO



HR2000 Series High-Resolution Fiber Optic Spectrometer



SPECTROMETER SPECIFICATIONS:

Grating: UV-VIS; Groove density: 600; Blaze@400nm

Collimating mirror: 0.22NA

Focal length: f/4, 101 mm; Entrance Aperture: 50 μ m

Data Transfer rate: Full scans into memory every 13 msec

LINEAR CCD SI ARRAY SPECIFICATIONS:

Detector range: 200-1100nm

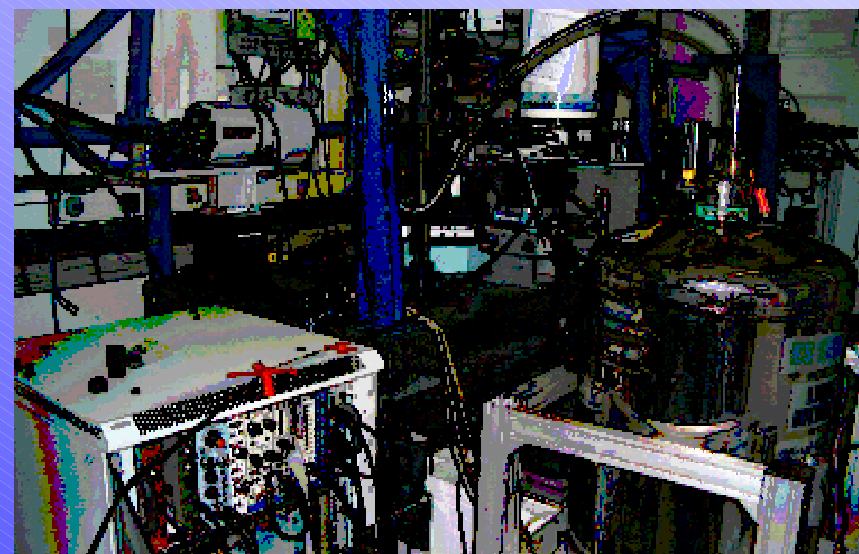
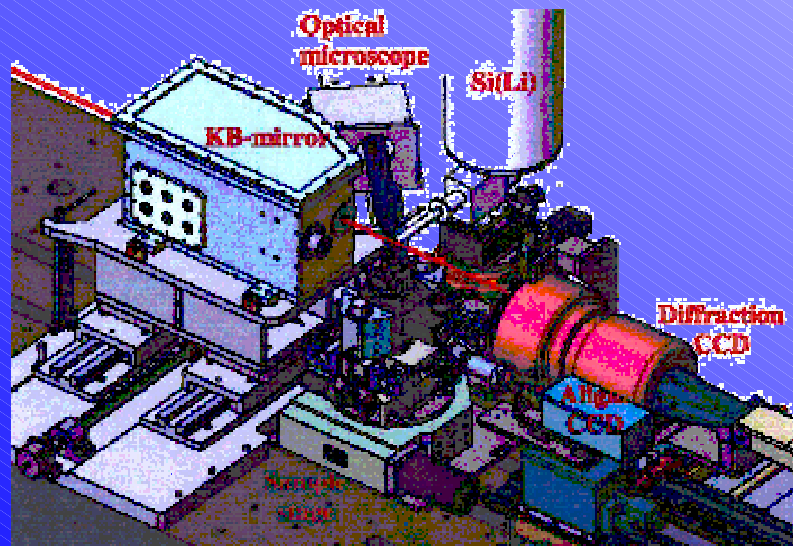
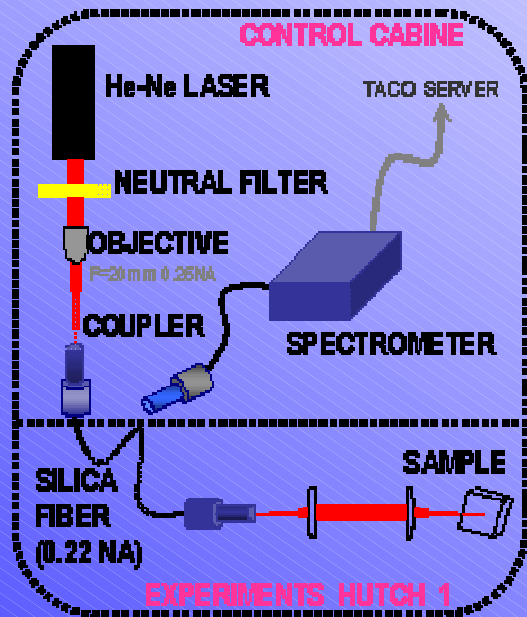
Pixel elements: 2048;

Signal-to-Noise: 260:1 (at full signal)

A/D Resolution: 12 bit

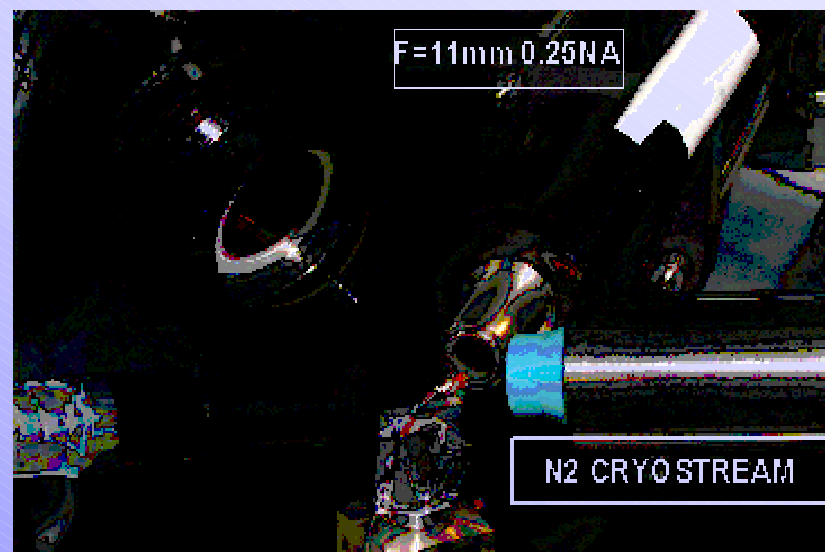
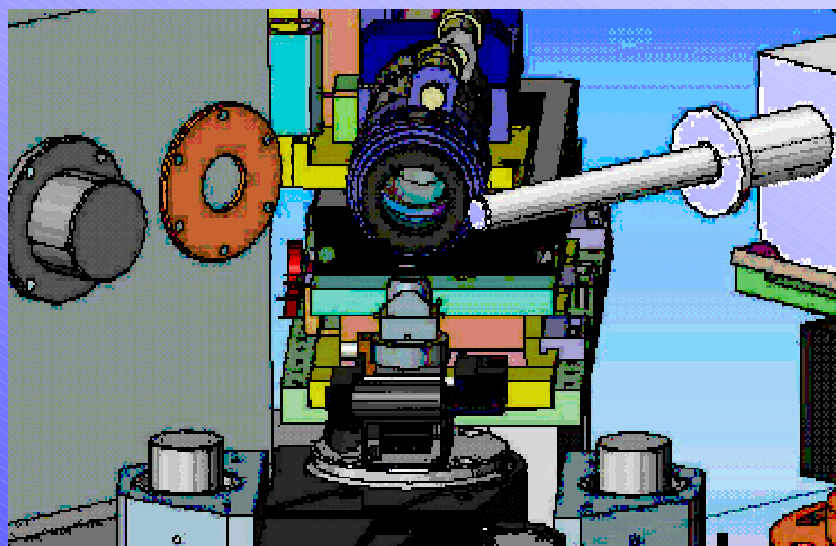
Dark Noise: 2.5 RMS counts

OPTICAL SYSTEM ALIGNMENT

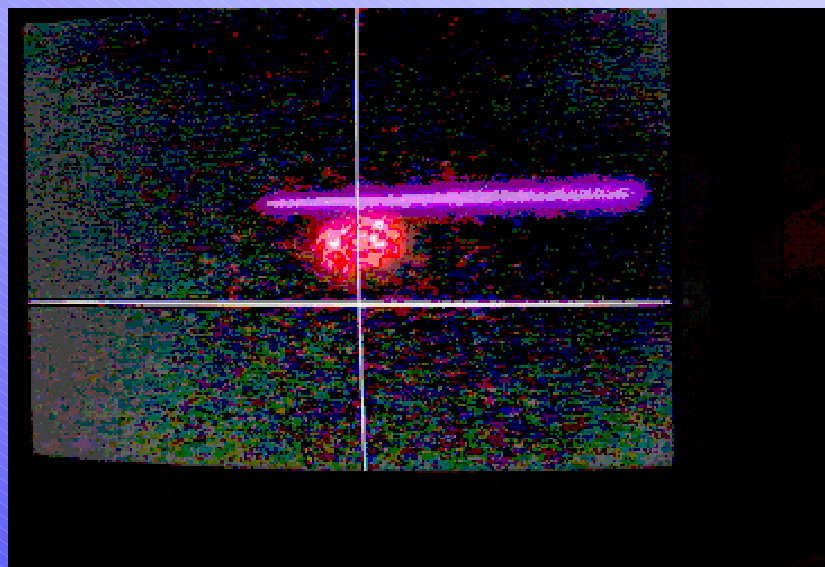
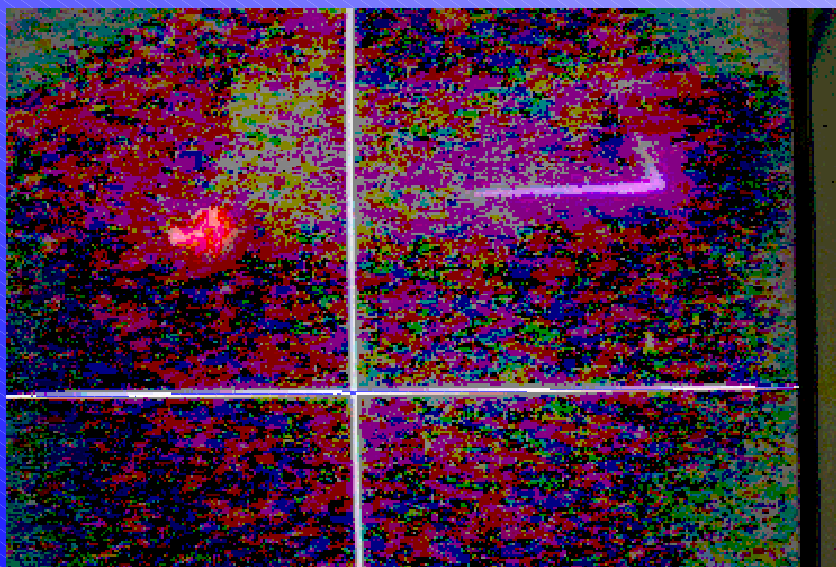


SETUP OF SCANNING μ X-RAY EXCITED

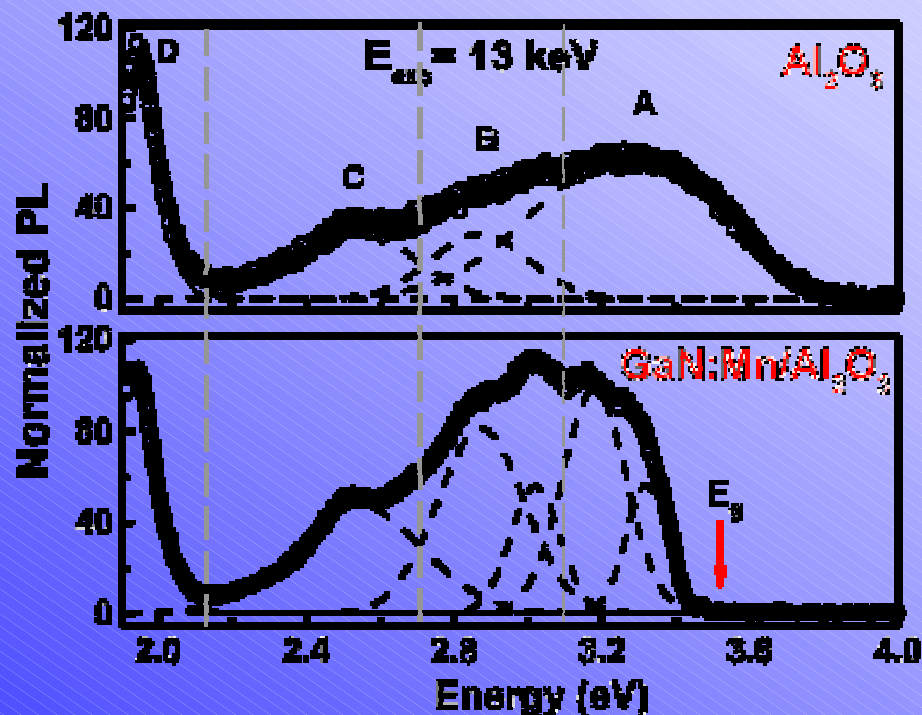
SAMPLE STAGE AT EXPERIMENTS HUTCH 1:



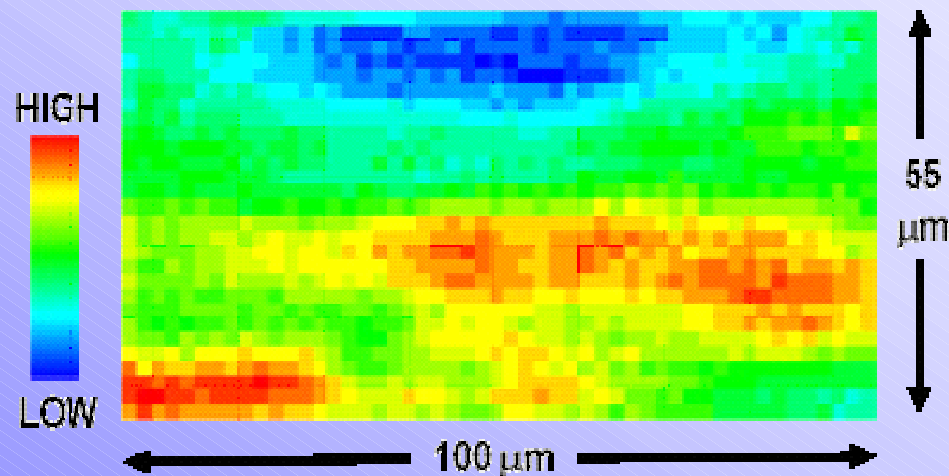
ALIGNMENT PROCEDURE AT THE CONTROL CABINE BY MEANS OF MICROSCOPE CCD:



FIRST DATA



GaN:Mn/Al₂O₃; [Mn]=11%; AVERAGE PL SPECTRA TAKEN AT ~80 K:



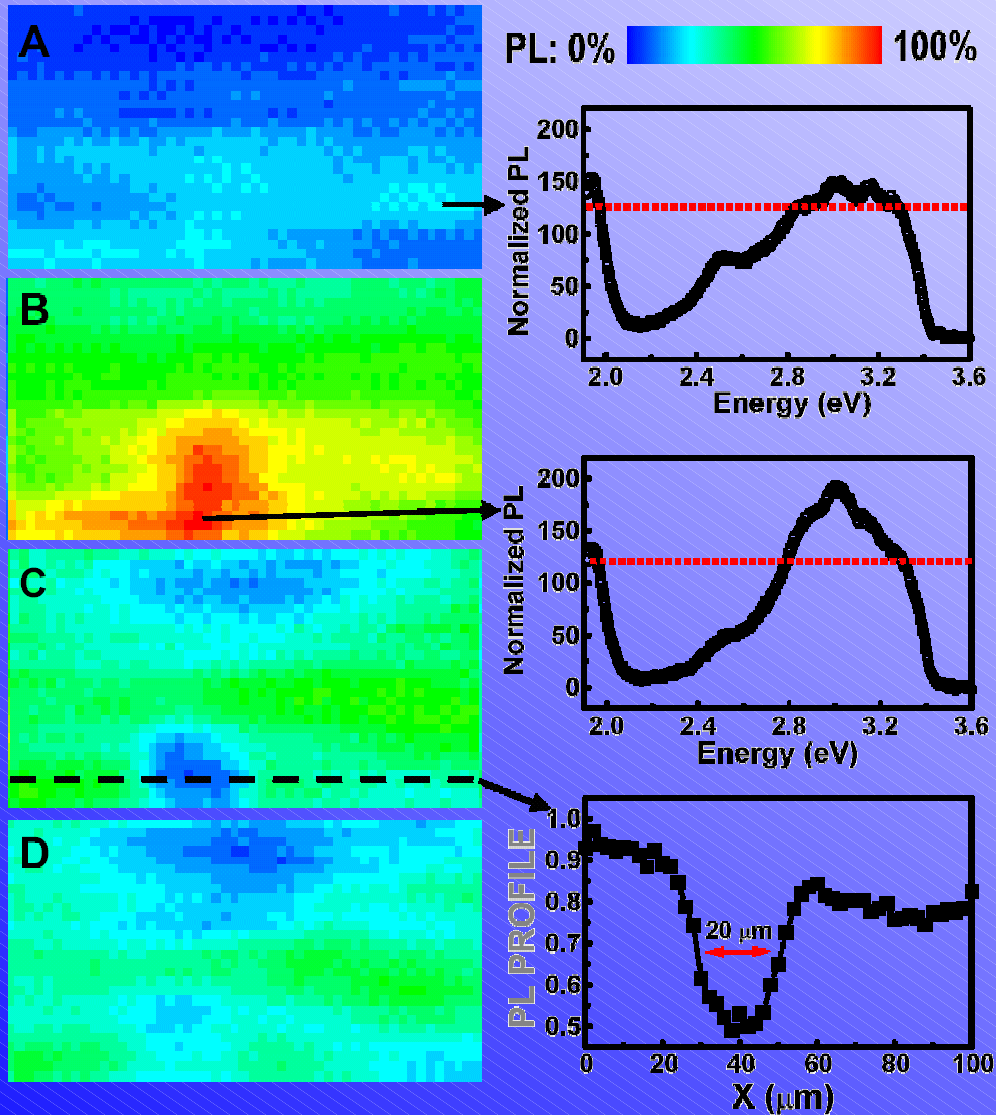
Spectral analysis:

- Background luminescence from sapphire substrate
- High energy tail from the sapphire absorbed by GaN
- Both Al₂O₃- and GaN:Mn-related transitions are overlapping



- 2D electron-hole recombination: non-uniform pattern
- Energy positions remains constant over the map: no large stress variation
- Though different sampling depths, good agreement with XRF: inhomogeneous Mn incorporation

PL IMAGING BY CORE-LEVEL EXCITATION



Spatial PL analysis:

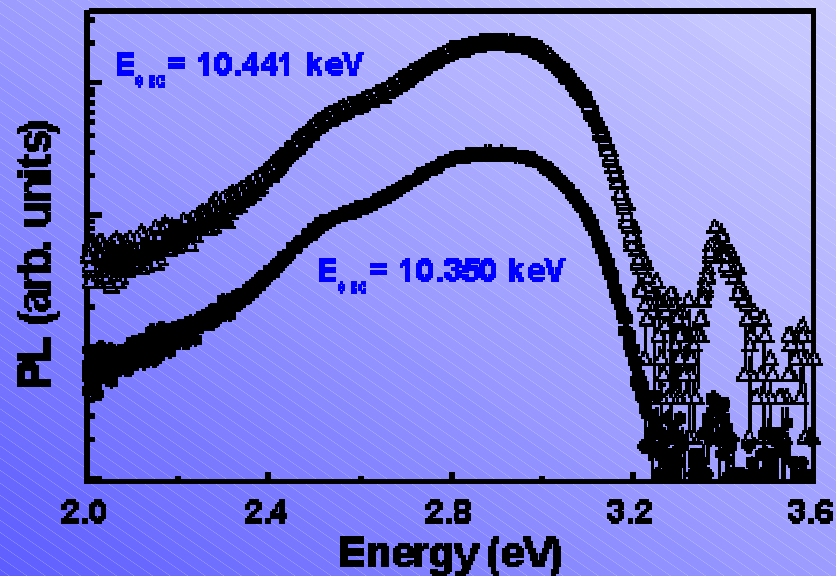
- Two kinds of optical shapes:
 - a few well-defined and sharp circular features
 - more recurrent structures horizontally elongated
- **C**: Mn-rich region absorbs the signal at 2.55 eV from sapphire
- **D**: Mn clusters block and interfere the Cr-related line
- **A,B**: strong variation of radiative rates



High energy bands at 2.7–3.1 eV:
seems to be specific from some Mn
center location in the GaN surface.

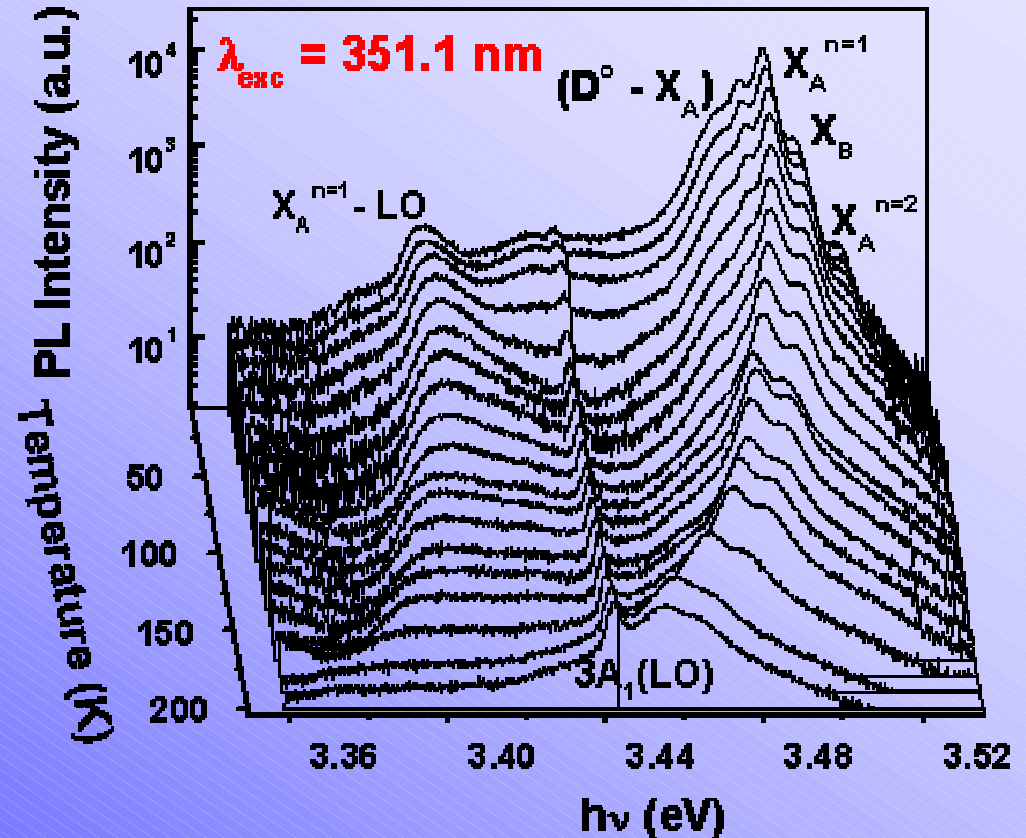
BUT, poor lateral resolution

XEOL IN FREE STANDING GaN LAYER @ Ga K-EDGE



Spectral analysis:

- Broad emissions insensitive to excitation energy
- Blue band at 2.9 eV: tentatively attributed to oxygen complexes
- Green band at 2.45 eV: commonly attributed to defects
- Excitons with very low intensities

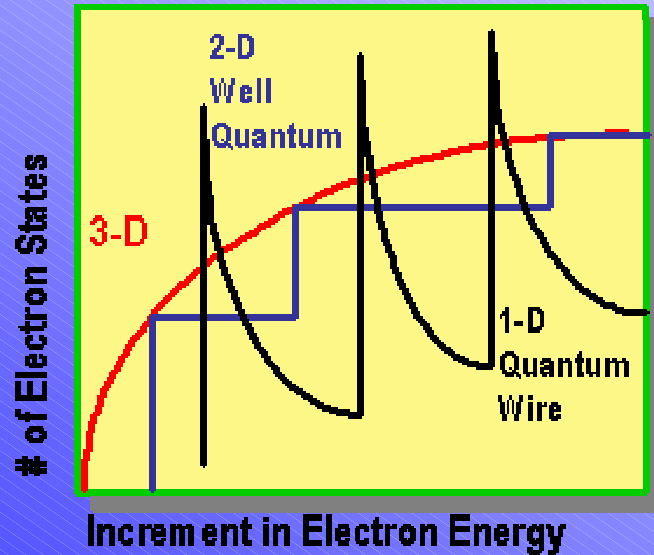


BUT, lower temperatures needed ...

... and better signal-to-noise ratio

THE NEAR FUTURE

The electronic states in III-V quantum heterostructures:



- Higher lateral resolution (NA)
- Extensions in wavelength
- Better signal-to-noise ratio



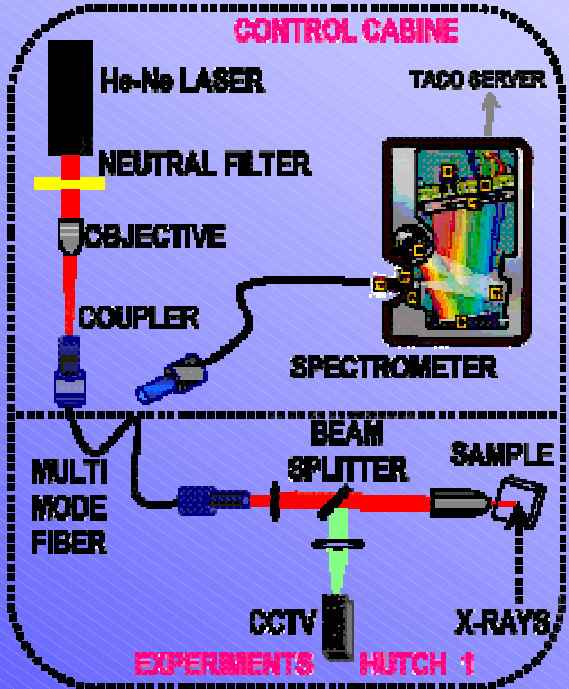
NIR WAVELENGTH DISPERSION

IN-LINE SAMPLE INSPECTION/ILLUMINATION

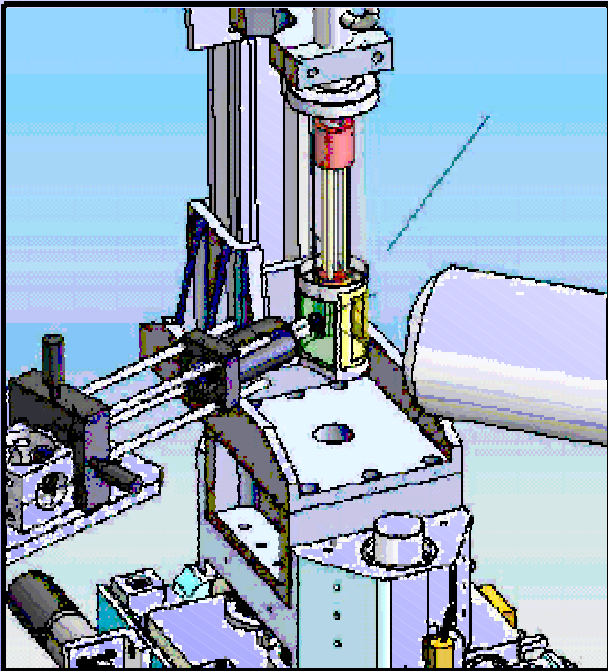
InGaAs COOLED MCD FOR IR LIGHT DETECTION

HELIUM MICRO-CRYOSTAT FOR XRF/XEOL MODES

UPGRADE IN PROGRESS



HE MICRO-CRYOSTAT



SPECTROMETER

CONCLUSIONS

- Scanning X-ray excited PL with micrometer resolution → feasible at ID22
- Alignment procedure → X-ray microbeam + Auxilliary laser spot
- GaN:Mn PL patterns → similar features probed by XRF mappings
- GaN XEOL on the micrometer scale → Successful
- Optical Detection Lateral Resolution → Needs improvements

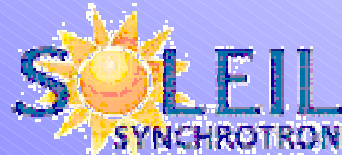
XEOL IN NANOSCALE:

- Silicon nanowires PRB70_045313 (2004)
- Porous silicon → LANGMUIR 20,4690(2004), NATURE 363,331 (1993)
- CdS nanoparticles → JAP 91, 6038 (2002)
- Organic LED Materials → Rev Sci Instrum 73, 1379 (2002)
- CdSe quantum dots → JCG 214, 752 (2000)

COLLABORATORS



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**Alejandro HOMS
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Jean SUSINI**



THANK YOU!